Product Preview

Low-Voltage CMOS Octal Registered Transceiver With Dual Output and Clock Enables

With 5V-Tolerant Inputs and Outputs (3-State, Non-Inverting)

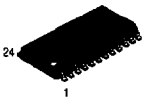
MC74LCX2952

LCX

LOW–VOLTAGE CMOS OCTAL REGISTERED TRANSCEIVER

The MC74LCX2952 is a high performance, non–inverting octal registered transceiver operating from a 2.7 to 3.6V supply. High impedance TTL compatible inputs significantly reduce current loading to input drivers while TTL compatible outputs offer improved switching noise performance. A V_I specification of 5.5V allows MC74LCX2952 inputs to be safely driven from 5V devices. The MC74LCX2952 is suitable for memory address driving and all TTL level bus oriented transceiver applications.

Two 8–bit back to back registers store data from either of two bidirectional buses. Data applied to the inputs is entered and stored on the rising edge of the Clock (CAB, CBA) provided that the Clock Enable ($\overline{CEAB}$, $\overline{CEBA}$) is Low. The data is then presented at the 3–state output buffers, but is only accessible when the Output Enable ($\overline{OEAB}$, $\overline{OEBA}$) is Low. The operation of the MC74LCX2952 is symmetrical — A inputs to B outputs occurs in the same manner as B inputs to A outputs.



DW SUFFIX
PLASTIC SOIC
CASE 751E–04

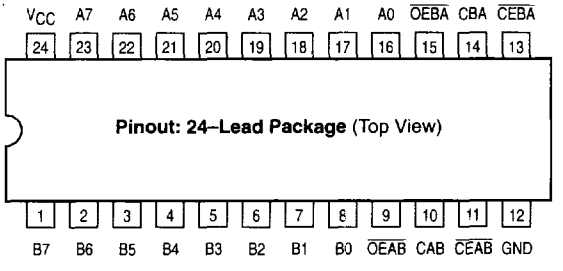
SD SUFFIX
PLASTIC SSOP
CASE 940D–03

DT SUFFIX
PLASTIC TSSOP
CASE 948H–01

- Designed for 2.7 to 3.6V V_{CC} Operation
- 5V Tolerant — Interface Capability With 5V TTL Logic
- Supports Live Insertion and Withdrawal
- I_{OFF} Specification Guarantees High Impedance When V_{CC} = 0V
- LVTTL Compatible
- LVCMOS Compatible
- 24mA Balanced Output Sink and Source Capability
- Near Zero Static Supply Current in All Three Logic States (10μA) Substantially Reduces System Power Requirements
- Latchup Performance Exceeds 500mA
- ESD Performance: Human Body Model >2000V; Machine Model >200V

PIN NAMES

Pins	Function
A0–A7	Side A Inputs/Outputs
B0–B7	Side B Inputs/Outputs
CAB, CBA	Clock Pulse Inputs
$\overline{CEAB}$, $\overline{CEBA}$	Clock Enable Inputs
$\overline{OEAB}$, $\overline{OEBA}$	Output Enable Inputs



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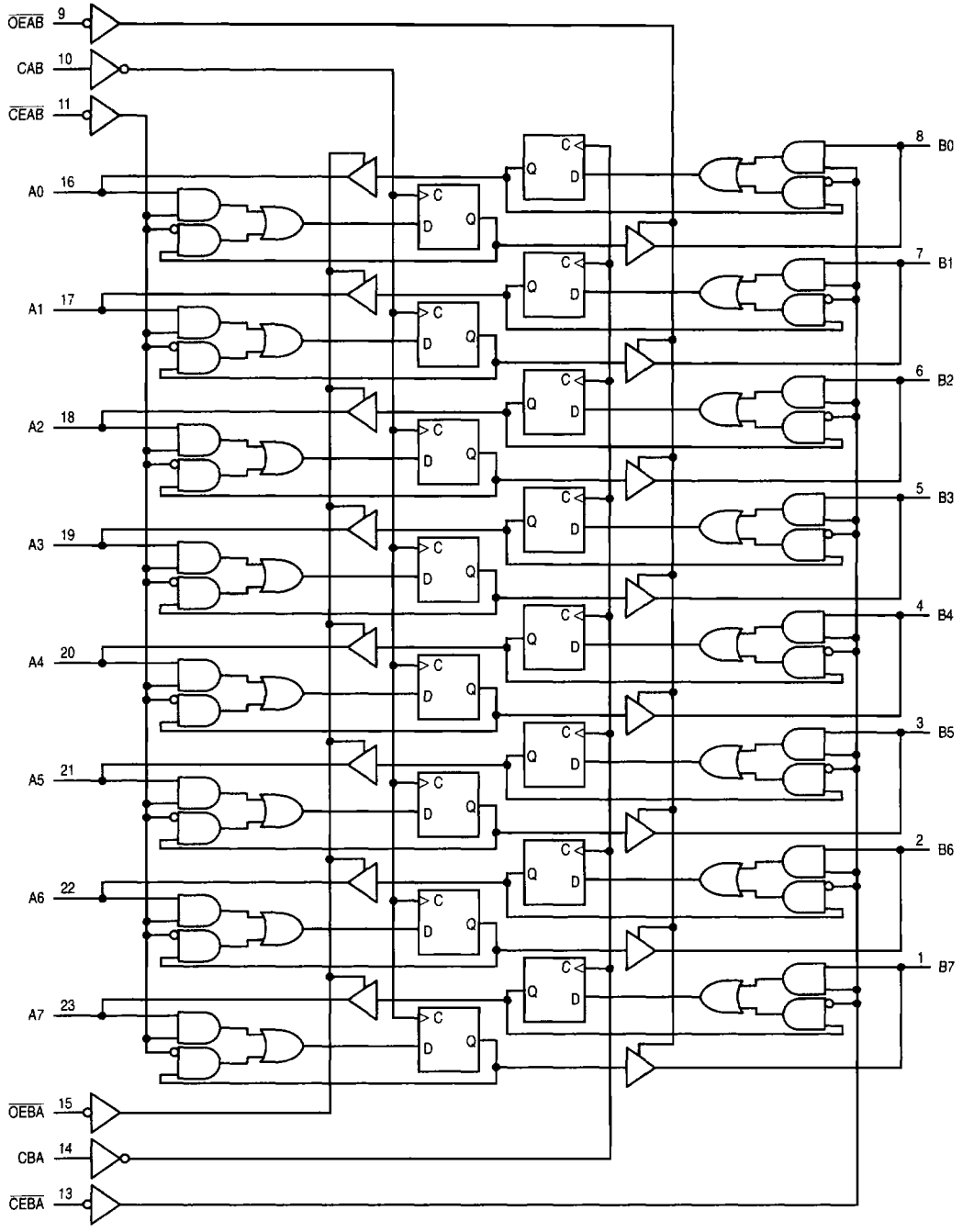
LOGIC DIAGRAM



FUNCTION TABLE

Inputs						Data Ports		Operating Mode
$\overline{OEAB}$	$\overline{OEBA}$	$\overline{CEAB}$	$\overline{CEBA}$	CAB	CBA	An	Bn	
H	H					Input	Input	
		l	l	↑	↑	X	X	Load Register; Disable Outputs
				↕	↕	X	X	Hold; Disable Outputs
		h	h	X	X	X	X	Hold; Disable Outputs
L	H					Input	Output	
		l	X	↑	X	l h	L H	Load A to B Register; Read B Output
				↕	X	X	QA	Hold; Read B Output
		h	X	X	X	X	QA	Hold; Read B Output
H	L					Output	Input	
		X	l	X	↑	L H	l h	Load B to A Register; Read A Output
				X	↕	QB	X	Hold; Read A Output
		X	h	X	X	QB	X	Hold; Read A Output

H = High Voltage Level; h = High Voltage Level One Setup Time Prior to the Low–to–High Clock Transition; L = Low Voltage Level; l = Low Voltage Level One Setup Time Prior to the Low–to–High Clock Transition; X = Don't Care; ↑ = Low–to–High Clock Transition; ↕ = NOT Low–to–High Clock Transition; QA = A input storage register; QB = B input storage register; * = The clocks are not internally gated with either the Output Enables or the Source Inputs. Therefore, data at the A or B ports may be clocked into the storage registers, at any time. For I_{CC} reasons, Do Not Float Inputs.

ABSOLUTE MAXIMUM RATINGS*

Symbol	Parameter	Value	Condition	Unit
V_{CC}	DC Supply Voltage	–0.5 to +7.0		V
V_I	DC Input Voltage	$-0.5 \le V_I \le +7.0$		V
V_O	DC Output Voltage	$-0.5 \le V_O \le +7.0$	Output in 3–State	V
		$-0.5 \le V_O \le V_{CC} + 0.5$	Note 1.	V
I_{IK}	DC Input Diode Current	–50	V_I < GND	mA
I_{OK}	DC Output Diode Current	–50	V_O < GND	mA
		+50	$V_O > V_{CC}$	mA
I_O	DC Output Source/Sink Current	±50		mA
I_{CC}	DC Supply Current Per Supply Pin	±100		mA
I_{GND}	DC Ground Current Per Ground Pin	±100		mA
T_{STG}	Storage Temperature Range	–65 to +150		°C

* Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute–maximum–rated conditions is not implied.

1. Output in HIGH or LOW State. I_O absolute maximum rating must be observed.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter		Min	Typ	Max	Unit
V_{CC}	Supply Voltage	Operating Data Retention Only	2.0 1.5	3.3 3.3	3.6 3.6	V
V_I	Input Voltage		0		5.5	V
V_O	Output Voltage	(HIGH or LOW State) (3–State)	0 0		V_{CC} 5.5	V
I_{OH}	HIGH Level Output Current, V_{CC} = 3.0V – 3.6V				–24	mA
I_{OL}	LOW Level Output Current, V_{CC} = 3.0V – 3.6V				24	mA
I_{OH}	HIGH Level Output Current, V_{CC} = 2.7V – 3.0V				–12	mA
I_{OL}	LOW Level Output Current, V_{CC} = 2.7V – 3.0V				12	mA
T_A	Operating Free–Air Temperature		–40		+85	°C
$\Delta t/\Delta V$	Input Transition Rise or Fall Rate. V_{IN} from 0.8V to 2.0V, V_{CC} = 3.0V		0		10	ns/V

DC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic	Condition	T_A = –40°C to +85°C		Unit
			Min	Max	
V_{IH}	HIGH Level Input Voltage (Note 2.)	2.7V ≤ V_{CC} ≤ 3.6V	2.0		V
V_{IL}	LOW Level Input Voltage (Note 2.)	2.7V ≤ V_{CC} ≤ 3.6V		0.8	V
V_{OH}	HIGH Level Output Voltage	2.7V ≤ V_{CC} ≤ 3.6V; I_{OH} = –100µA	V_{CC} – 0.2		V
		V_{CC} = 2.7V; I_{OH} = –12mA	2.2		
		V_{CC} = 3.0V; I_{OH} = –18mA	2.4		
		V_{CC} = 3.0V; I_{OH} = –24mA	2.2		
V_{OL}	LOW Level Output Voltage	2.7V ≤ V_{CC} ≤ 3.6V; I_{OL} = 100µA		0.2	V
		V_{CC} = 2.7V; I_{OL}= 12mA		0.4	
		V_{CC} = 3.0V; I_{OL} = 16mA		0.4	
		V_{CC} = 3.0V; I_{OL} = 24mA		0.55	
I_I	Input Leakage Current	2.7V ≤ V_{CC} ≤ 3.6V; 0V ≤ V_I ≤ 5.5V		±5.0	µA
I_{OZ}	3–State Output Current	2.7 ≤ V_{CC} ≤ 3.6V; 0V ≤ V_O ≤ 5.5V; V_I = V_{IH} or V_{IL}		±5.0	µA
I_{OFF}	Power–Off Leakage Current	V_{CC} = 0V; V_I or V_O = 5.5V		10	µA
I_{CC}	Quiescent Supply Current	2.7 ≤ V_{CC} ≤ 3.6V; V_I = GND or V_{CC}		10	µA
		2.7 ≤ V_{CC} ≤ 3.6V; 3.6 ≤ V_I or V_O ≤ 5.5V		±10	µA
ΔI_{CC}	Increase in I_{CC} per Input	2.7 ≤ V_{CC} ≤ 3.6V; V_{IH} = V_{CC} – 0.6V		500	µA

2. These values of V_I are used to test DC electrical characteristics only.

AC CHARACTERISTICS (Note 3.; $t_R = t_F = 2.5ns$; $C_L = 50pF$; $R_L = 500\Omega$)

Symbol	Parameter	Waveform	Limits				Unit
			$T_A = -40°C$ to $+85°C$				
			$V_{CC} = 3.0V$ to $3.6V$		$V_{CC} = 2.7V$		
			Min	Max	Min	Max	
f_{max}	Clock Pulse Frequency	3	150				MHz
t_{PLH} t_{PHL}	Propagation Delay Clock to Output	1	1.5 1.5	8.5 8.5	1.5 1.5	9.5 9.5	ns
t_{PZH} t_{PZL}	Output Enable Time to High and Low Level	2	1.5 1.5	8.5 8.5	1.5 1.5	9.5 9.5	ns
t_{PHZ} t_{PLZ}	Output Disable Time From High and Low Level	2	1.5 1.5	8.5 8.5	1.5 1.5	9.5 9.5	ns
t_s	Setup Time, HIGH to LOW Data to Clock	3	2.5		2.5		ns
t_h	Hold Time, HIGH to LOW Data to Clock	3	1.5		1.5		ns
t_s	Setup Time, HIGH to LOW $\overline{CExx}$ to Clock	3	2.5		2.5		ns
t_h	Hold Time, HIGH to LOW $\overline{CExx}$ to Clock	3	1.5		1.5		ns
t_w	Clock Pulse Width, HIGH or LOW	3	3.3		3.3		ns
t_{OSHL} t_{OSLH}	Output–to–Output Skew (Note 4.)			1.0 1.0			ns

3. These AC parameters are preliminary and may be modified prior to release. The maximum AC limits are design targets. Actual performance will be specified upon completion of characterization.
4. Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH–to–LOW (t_{OSHL}) or LOW–to–HIGH (t_{OSLH}); parameter guaranteed by design.

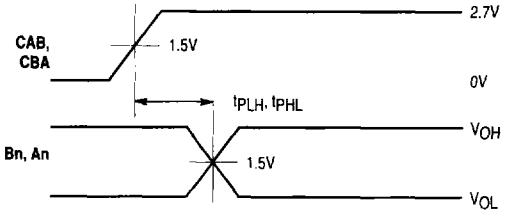
DYNAMIC SWITCHING CHARACTERISTICS

Symbol	Characteristic	Condition	$T_A = +25°C$			Unit
			Min	Typ	Max	
V_{OLP}	Dynamic LOW Peak Voltage (Note 5.)	$V_{CC} = 3.3V$, $C_L = 50pF$, $V_{IH} = 3.3V$, $V_{IL} = 0V$		0.8		V
V_{OLV}	Dynamic LOW Valley Voltage (Note 5.)	$V_{CC} = 3.3V$, $C_L = 50pF$, $V_{IH} = 3.3V$, $V_{IL} = 0V$		0.8		V

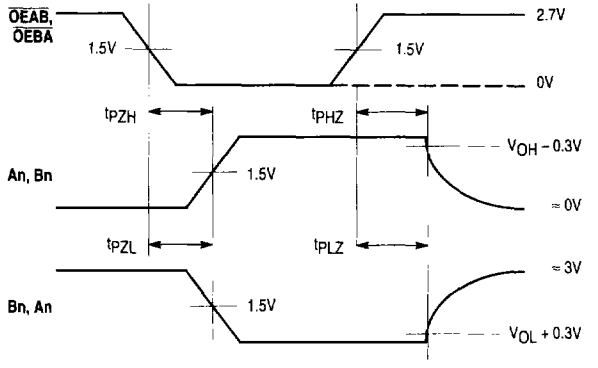
5. Number of outputs defined as "n". Measured with "n–1" outputs switching from HIGH–to–LOW or LOW–to–HIGH. The remaining output is measured in the LOW state.

CAPACITIVE CHARACTERISTICS

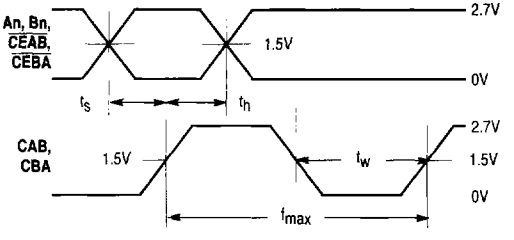
Symbol	Parameter	Condition	Typical	Unit
C_{IN}	Input Capacitance	$V_{CC} = 3.3V$, $V_I = 0V$ or V_{CC}	7	pF
$C_{I/O}$	Input/Output Capacitance	$V_{CC} = 3.3V$, $V_I = 0V$ or V_{CC}	8	pF
C_{PD}	Power Dissipation Capacitance	10MHz, $V_{CC} = 3.3V$, $V_I = 0V$ or V_{CC}	25	pF



WAVEFORM 1 – Cxx to An/Bn PROPAGATION DELAYS
$t_R = t_F = 2.5ns$, 10% to 90%; f = 1MHz; $t_W = 500ns$

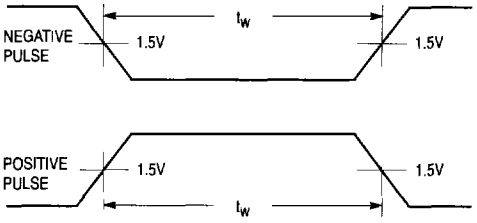


WAVEFORM 2 – $\overline{OExx}$ to An/Bn OUTPUT ENABLE AND DISABLE TIMES
$t_R = t_F = 2.5ns$, 10% to 90%; f = 1MHz; $t_W = 500ns$



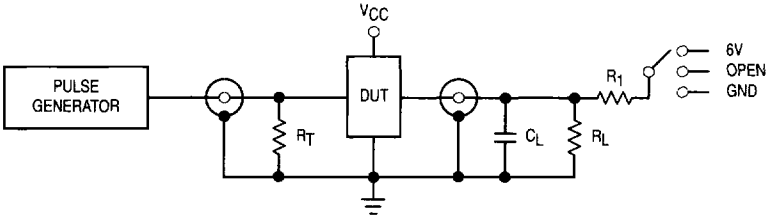
WAVEFORM 3 – Cxx MINIMUM PULSE WIDTH, An/Bn/$\overline{CExx}$ to Cxx SETUP AND HOLD TIMES
$t_R = t_F = 2.5ns$, 10% to 90%; f = 1MHz; $t_W = 500ns$ except when noted

Figure 1. AC Waveforms



WAVEFORM 4 – INPUT PULSE DEFINITION
$t_R = t_F$ = 2.5ns, 10% to 90% of 0V to 2.7V

Figure 2. AC Waveforms



TEST	SWITCH
t_{PLH}, t_{PHL}	Open
t_{PZL}, t_{PLZ}	6V
Open Collector/Drain t_{PLH} and t_{PHL}	6V
t_{PZH}, t_{PHZ}	GND

C_L = 50pF or equivalent (Includes jig and probe capacitance)
$R_L = R_1$ = 500Ω or equivalent
$R_T = Z_{OUT}$ of pulse generator (typically 50Ω)

Figure 3. Test Circuit